

THE ANISOTROPY AND SIGN CHANGE OF MAGNETORESISTANCE IN THE LAYERED QUASI ONE-DIMENSIONAL SEMICONDUCTOR TiS_3

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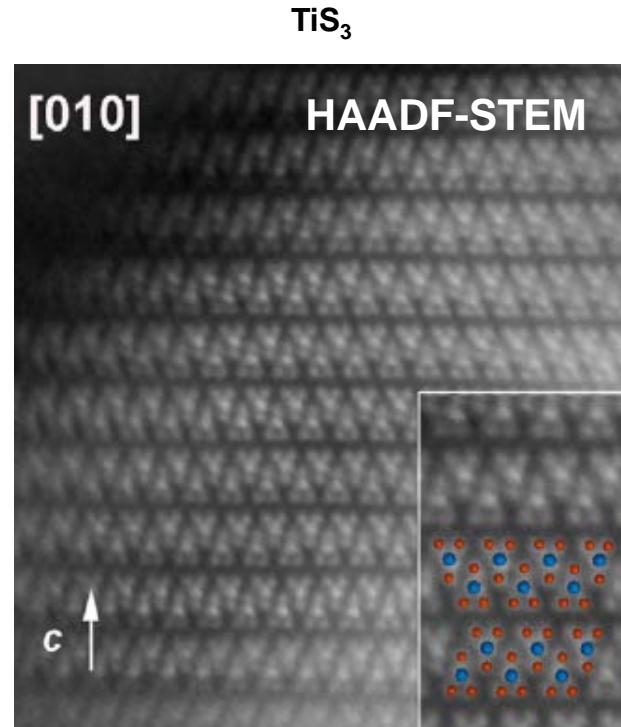
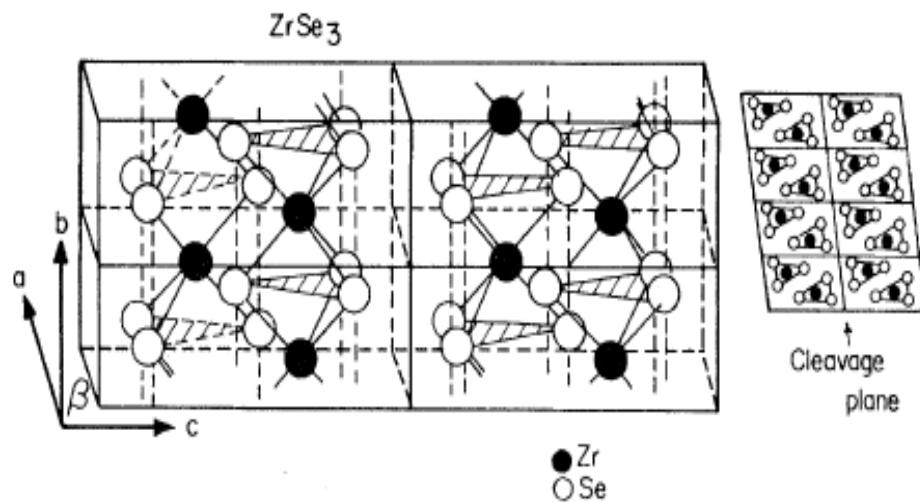
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Crystal structure of TiS_3

Transition metal trichalcogenides of Group IV metals. MX_3 , where $\text{M} = \text{Ti}, \text{Zr}, \text{Hf}$; and $\text{X} = \text{S}, \text{Se}, \text{Te}$, are layered quasi one-dimensional compounds. MX_3 are diamagnetic semiconductors. ZrTe_3 and TiS_3 show metallic properties. ZrTe_3 undergoes a phase transition at 63 K due to CDW formation.

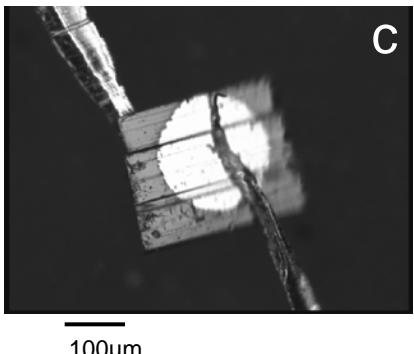
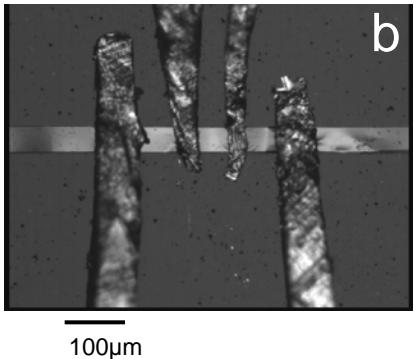
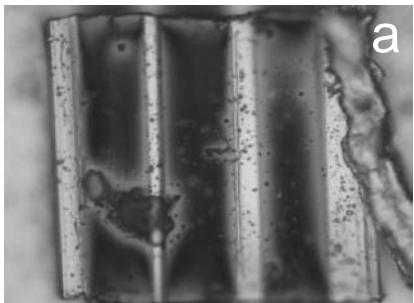


F.S. Khumalo and H.P. Hughes, Phys. Rev. B, **22** 2078 (1980)

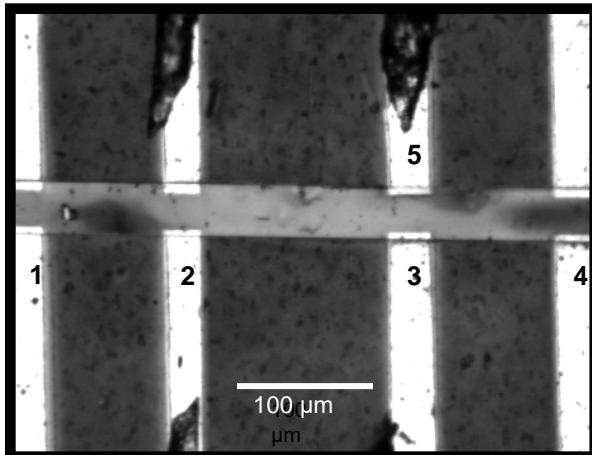
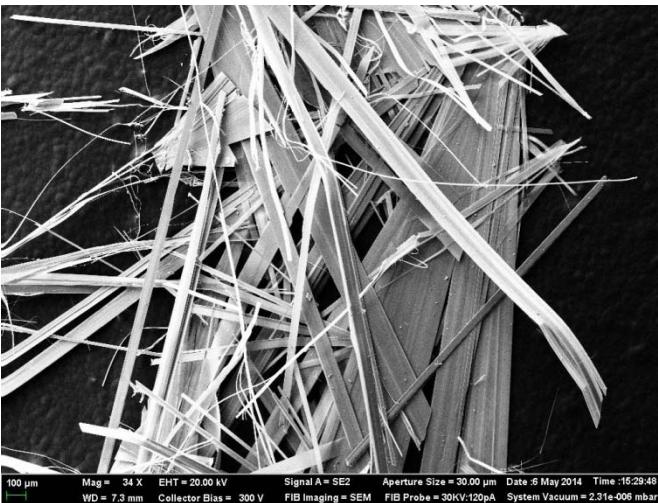
E. Guilmeau et.al., Chem. Mater., **26** 5585 (2014)

Unit cell parameters: $a=0.50 \text{ nm}$, $b=0.34 \text{ nm}$, $c=0.88 \text{ nm}$. $\beta=98,4^\circ$
Structural type – monoclinic. Space group – P21/m

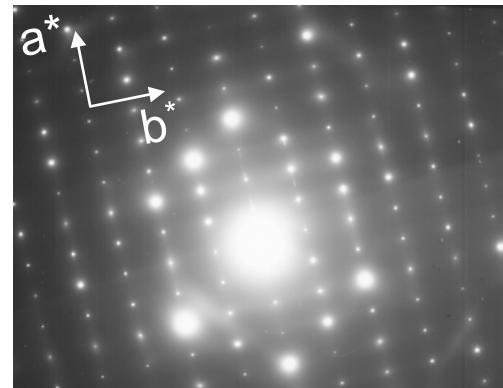
Samples



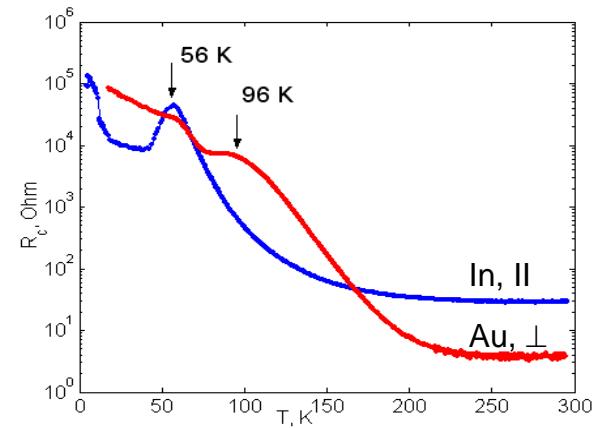
The TiS_3 whiskers with electrical contacts. The current flows along a -axis (a), b -axis (b), c -axis (c)



TiS_3 whisker (the gray stripe in the middle) with 8 Au contacts prepared for R_{xy} and R_{xx} measurements.

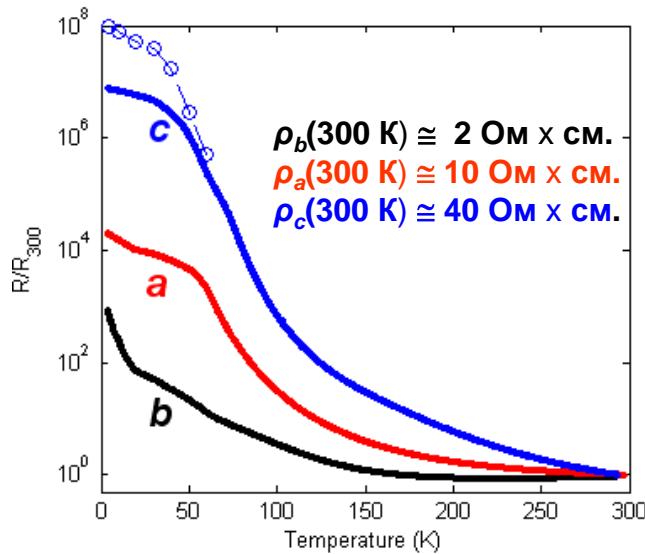


The diffraction patterns of the TiS_3 whisker at 285 K
HVEM JEM-1000

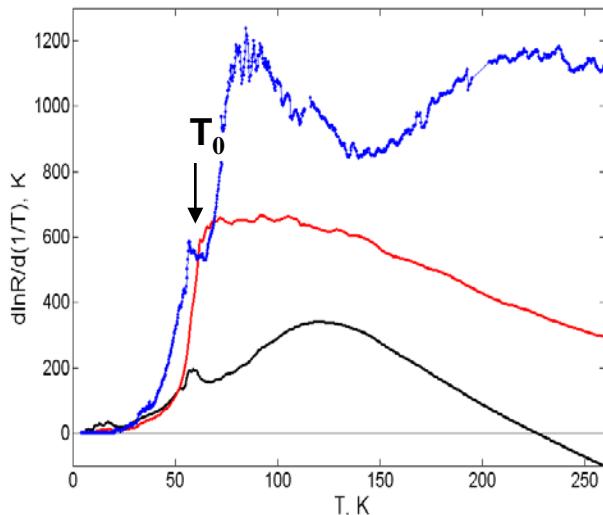


The temperature dependencies of the contact resistance to TiS_3 whiskers. Contact resistance at 300 K was $\sim 10^{-6}$ Ohm \times cm^2 .

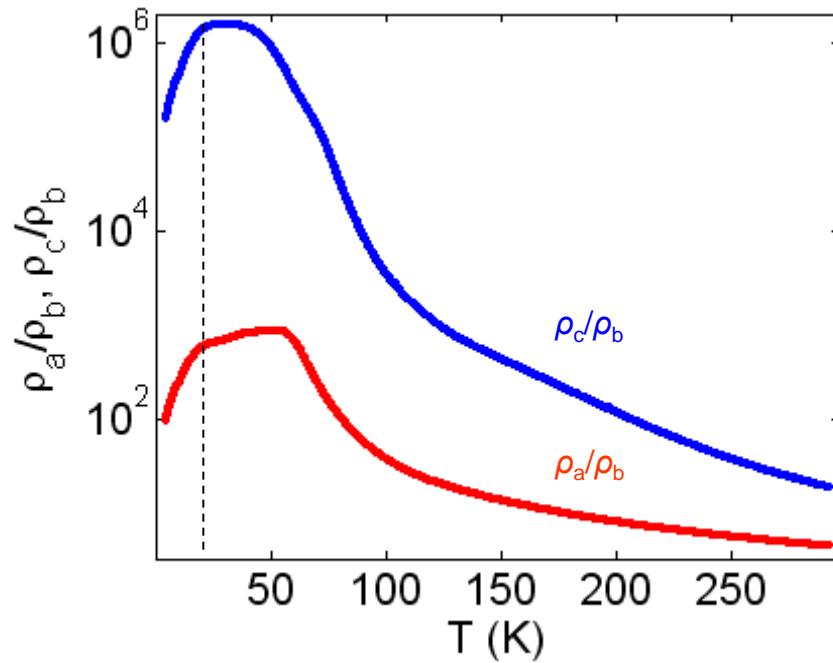
The anisotropy of conductivity of TiS_3 whiskers.



The temperature dependences of the resistance of TiS_3 , measured along the **a**, **b**, and **c** axes



The temperature dependences of the logarithmic derivatives $d \ln R / d(1/T)$ along the **a**, **b**, and **c** axes.

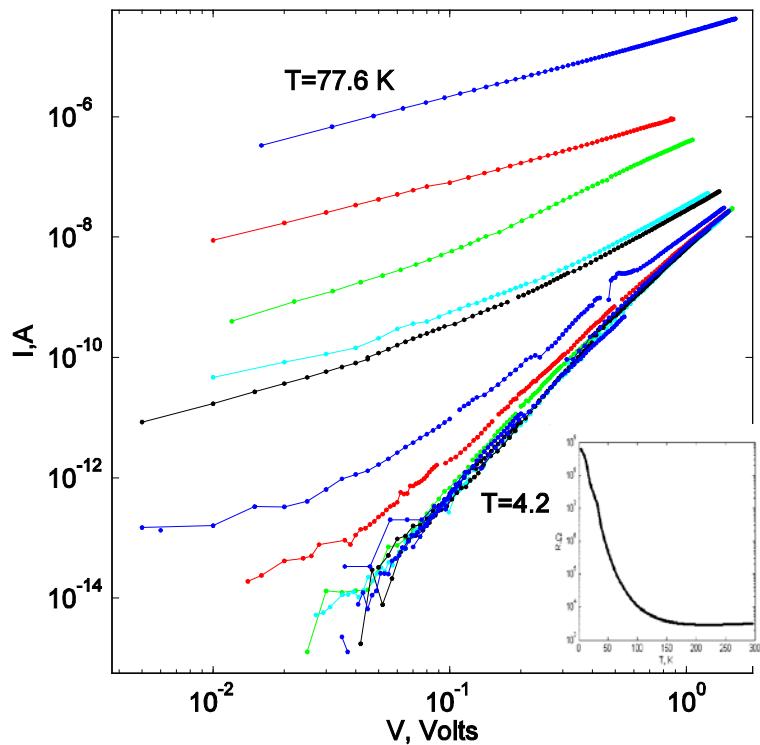


Temperature dependencies of the ratio ρ_a/ρ_b and ρ_c/ρ_b .
 $\rho_a/\rho_b \sim 5$; $\rho_c/\rho_b \sim 20$ at 300 K.
 $\rho_c \rho_a \rho_b \sim 10^6 : 10^3 : 1$ at $T=50 \text{ K}$.

Power-law behavior of conductivity in TiS_3 whiskers.

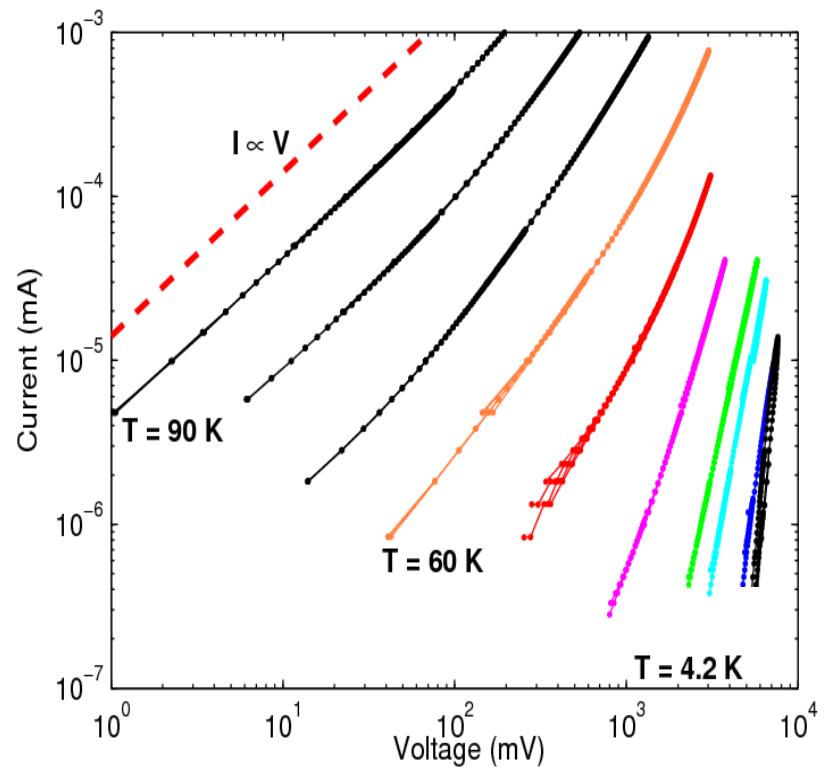
$$I \propto V^\alpha(T)$$

In the *ab* plane



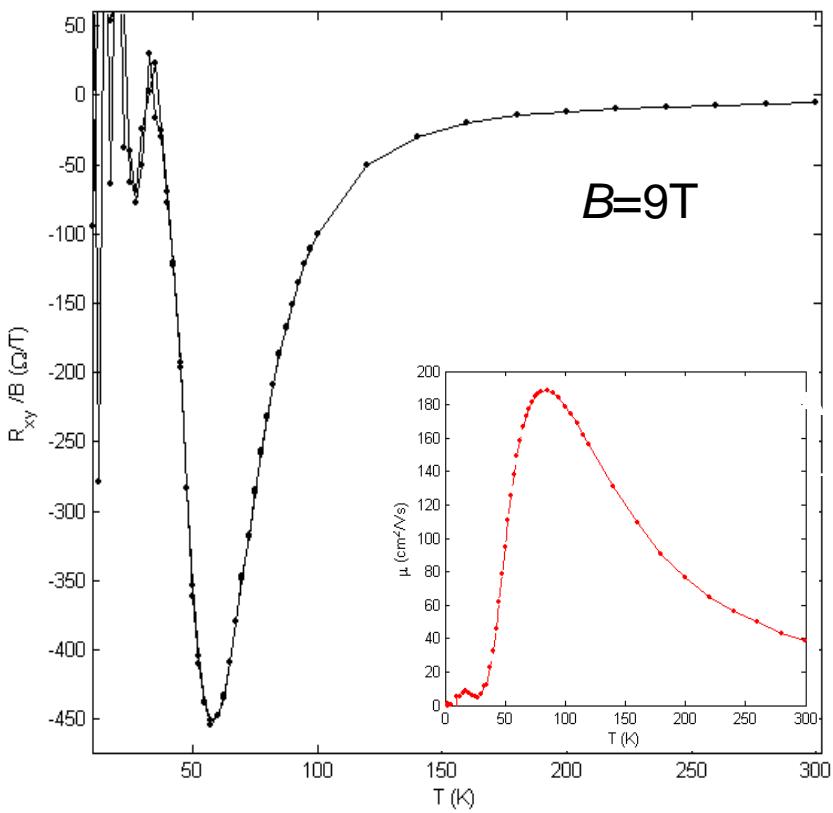
log I -log V curves measured along ***b*-axis**
at $T = 4.2, 5.2, 5.6, 6.4, 7.7, 12.8, 24.7, 26.6,$
 $41.5, 58.9, 77.6 \text{ K}$. Inset: $R(T)$ of the whiskers.
 $\rho_b(300 \text{ K}) = 0.2 \text{ Ohm} \times \text{cm}$.

Out-of-plane



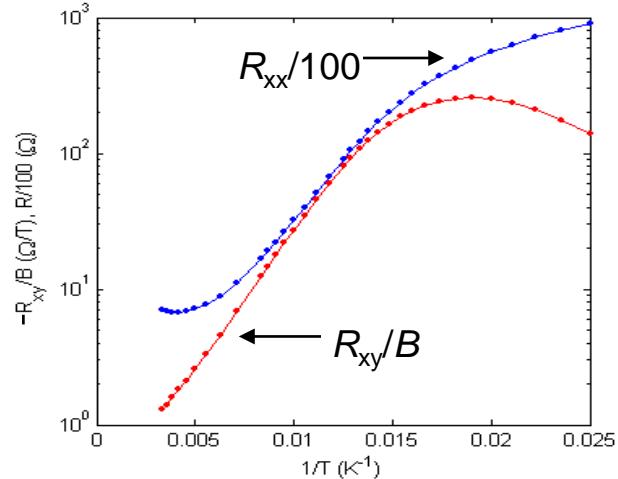
log I -log V curves measured along ***c*-axis**
at $T = 4.2, 10, 20, 30, 40, 50, 60, 70, 80, 90 \text{ K}$

Hall effect and magnetic susceptibility for TiS_3

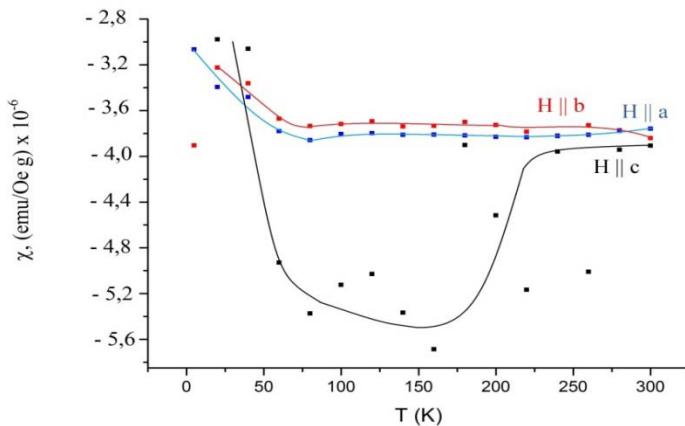


The temperature dependence of the Hall resistance for TiS_3 . Inset: temperature dependence of the Hall mobility. Electron density: $n_{300} \sim 10^{18} \text{ cm}^{-3}$, $n_{50} \sim 10^{15} \text{ cm}^{-3}$. Electron density per elementary conducting layer at 300 K is $\sim 10^{11} \text{ cm}^{-2}$, at 50 K - $\sim 5 \times 10^8 \text{ cm}^{-2}$

I.G. Gorlova et al., Physica B 460 11-15 (2015).



The temperature dependencies of the Hall resistance R_{xy} ($B=9\text{T}$) and b -axis resistance R_{xx} for the same whisker. The activation energy: for $R_{xx}=415\text{ K}$, for $R_{xy}=469\text{ K}$

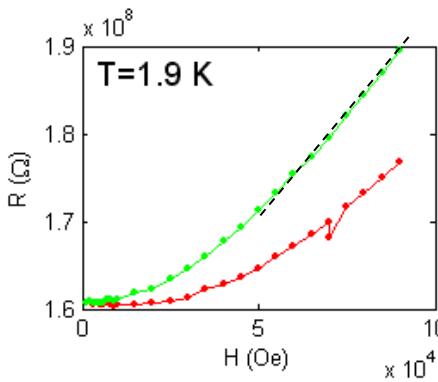
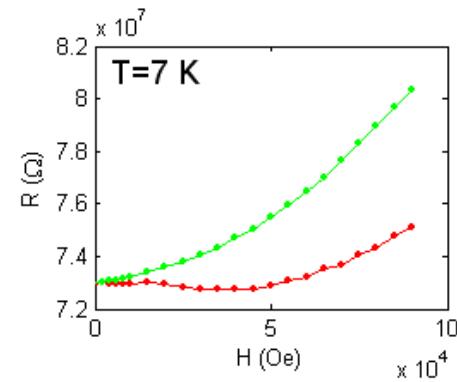
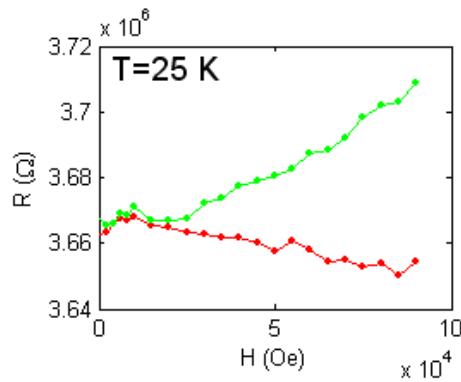
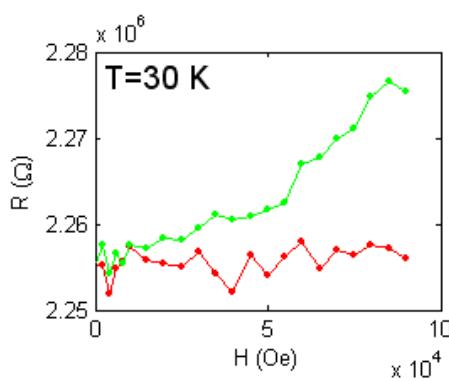
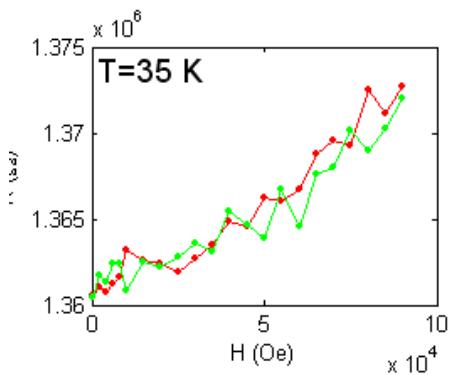
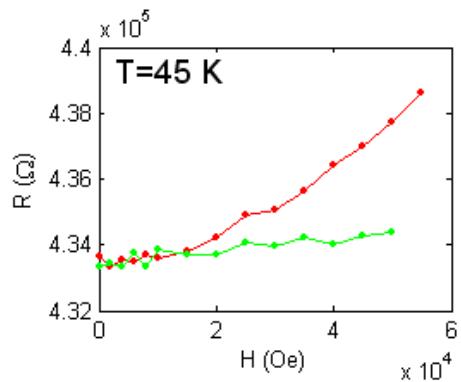
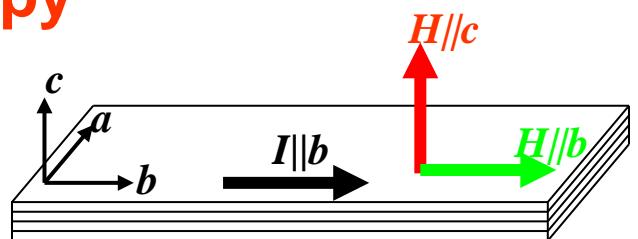


The temperature dependences of the magnetic susceptibility of TiS_3 along the a , b , and c axes.

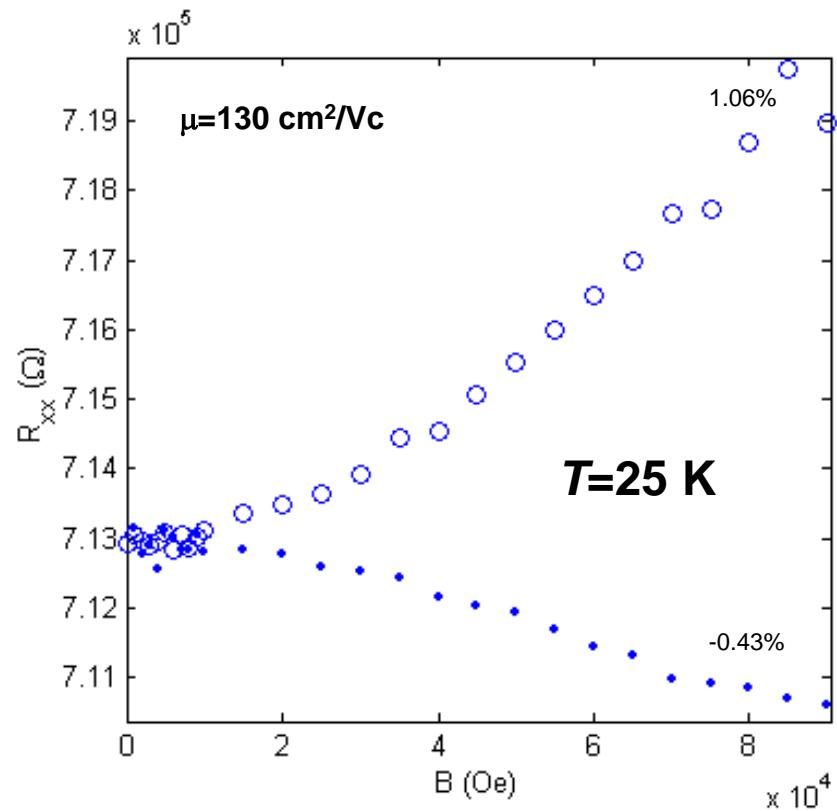
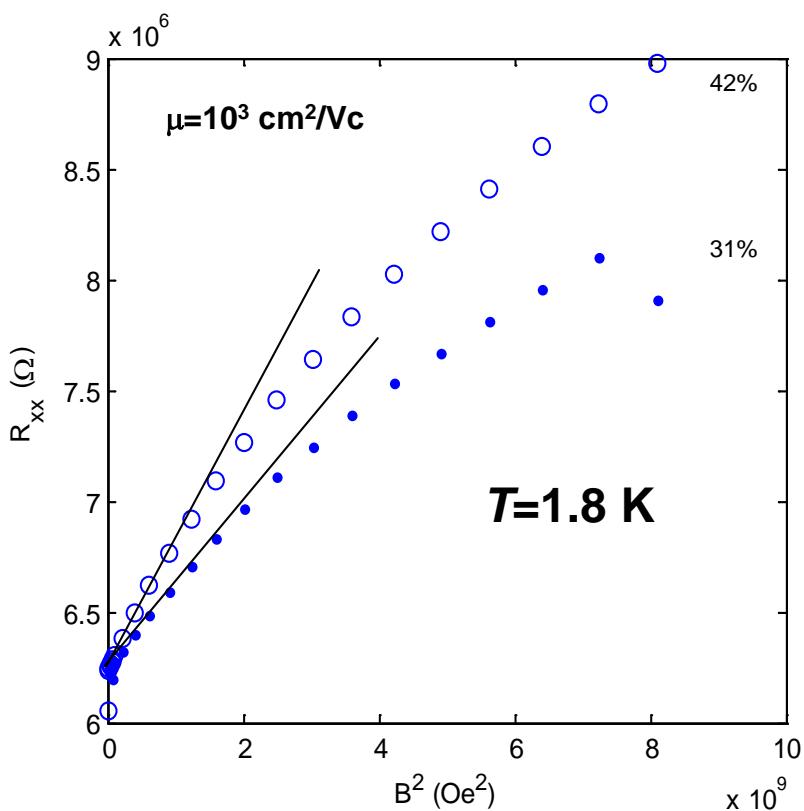
Magnetic field dependencies of *b*-axis resistance R_{xx} . *bc*-plane anisotropy

PPMS-9

$I \parallel b$, • - $H \parallel b$, • - $H \parallel c$



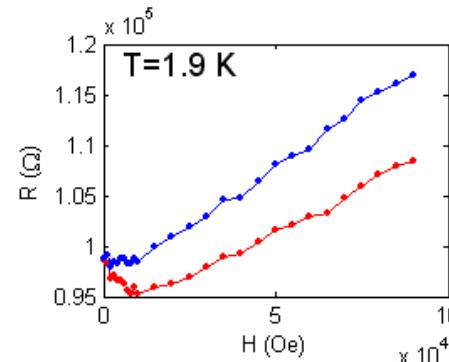
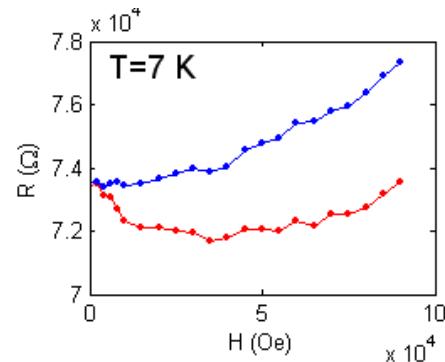
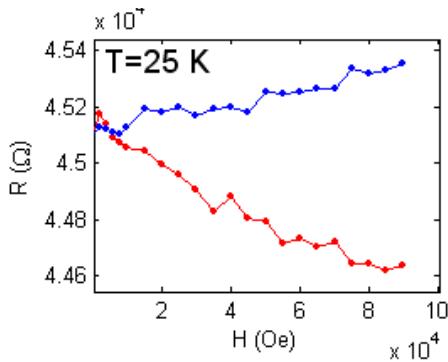
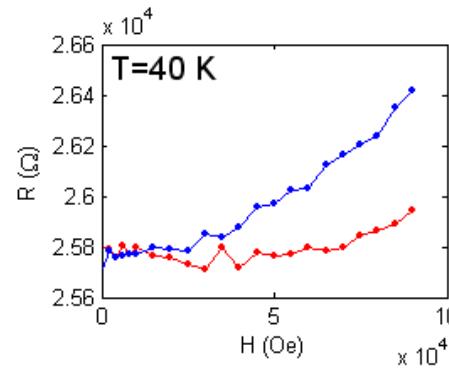
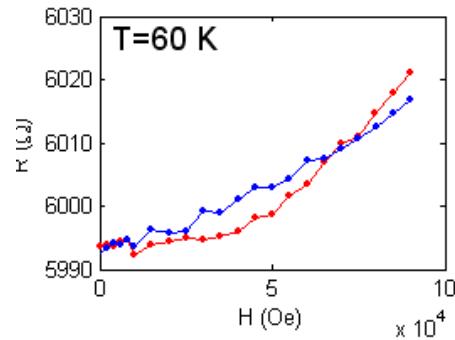
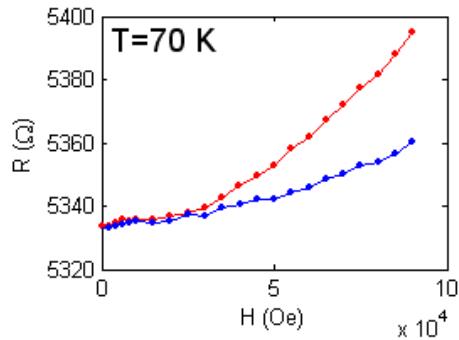
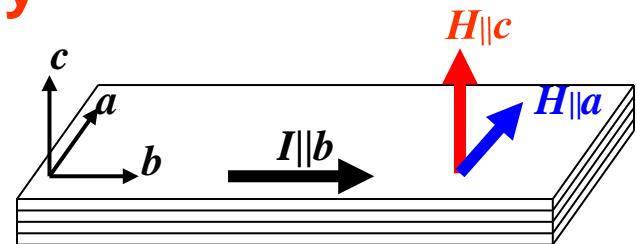
Magnetic field dependencies of *b*-axis resistance R_{xx}



out-of plane fields, $\mathbf{B} \parallel c$ (●), in-plane fields, $\mathbf{B} \parallel I \parallel b$ (○).

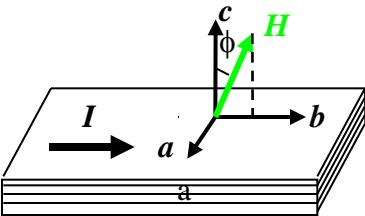
Magnetic field dependencies of *b*-axis resistance R_{xx} . ac-plane anisotropy

$H \perp I, I \parallel b, \bullet - H \parallel a, \bullet - H \parallel c$

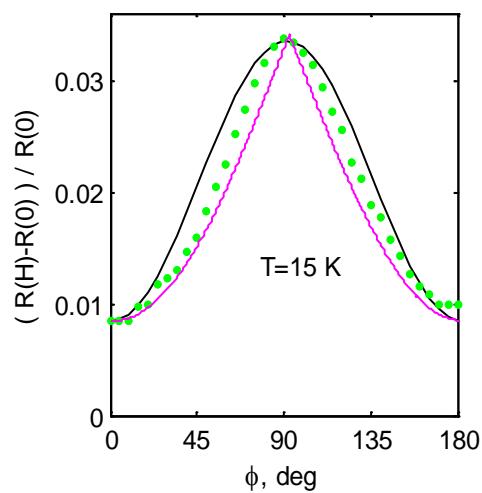


Angle dependences of magnetoresistance of TiS_3

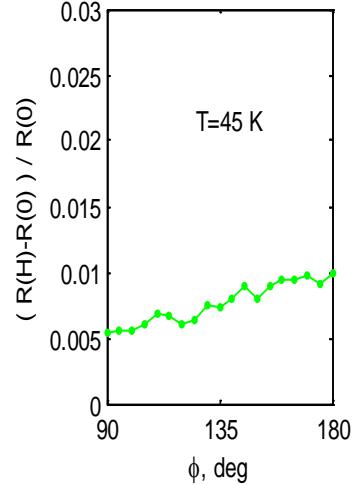
$H = 4 \times 10^4 \text{ Oe}$, $I \parallel b$



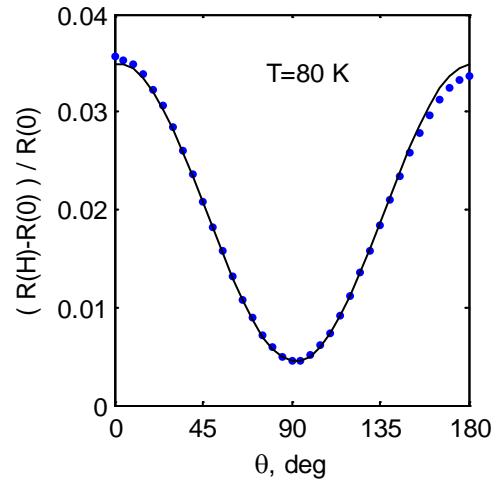
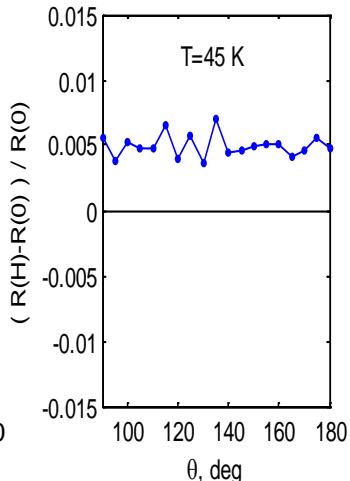
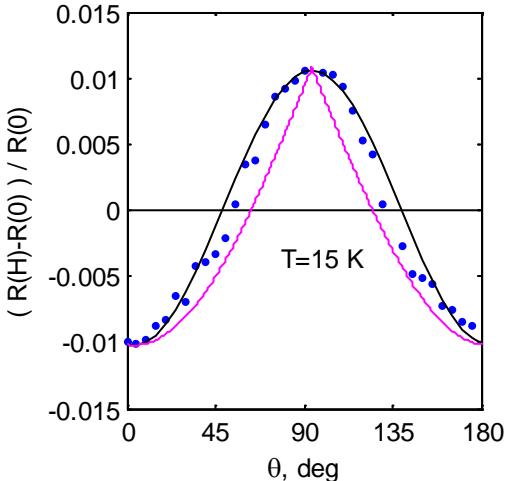
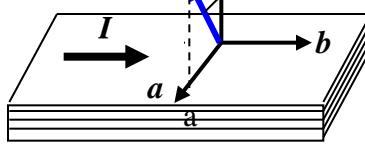
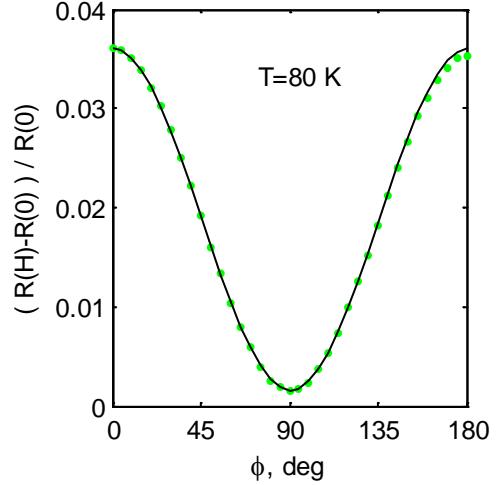
$T < T_0$



$T \approx T_0$

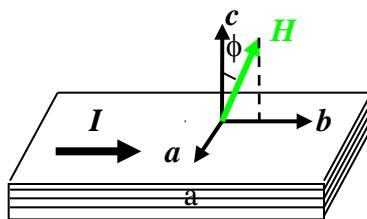


$T > T_0$

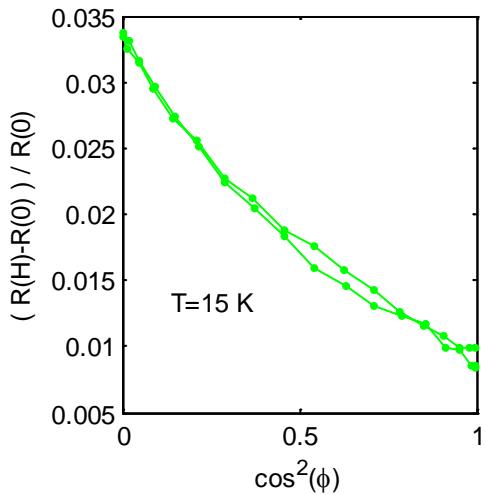


— $\cos(2\theta)$ or $\cos(2\phi)$
 — $|\cos(\theta)|$ or $|\cos(\phi)|$

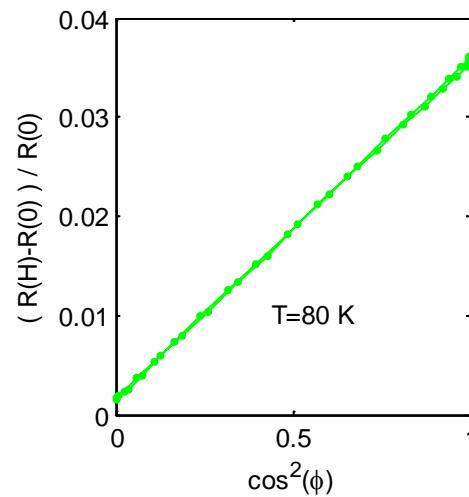
Angle dependences of magnetoresistance of TiS_3



$T < T_0$

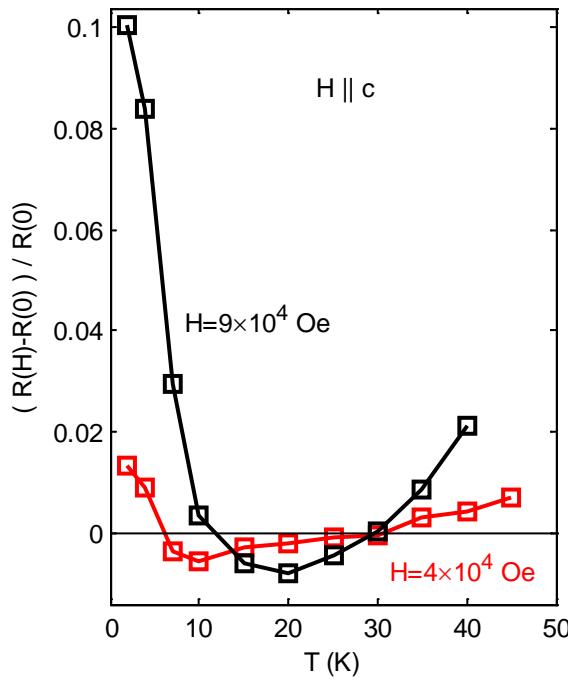
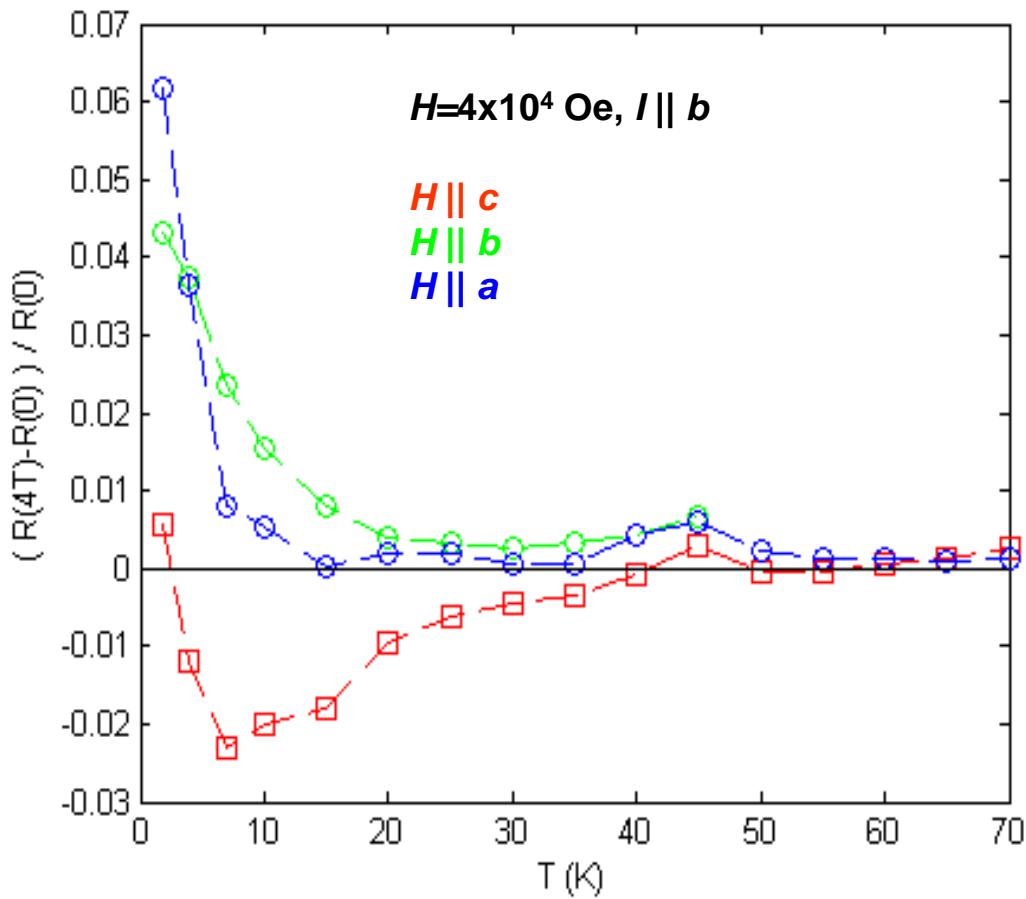


$T > T_0$



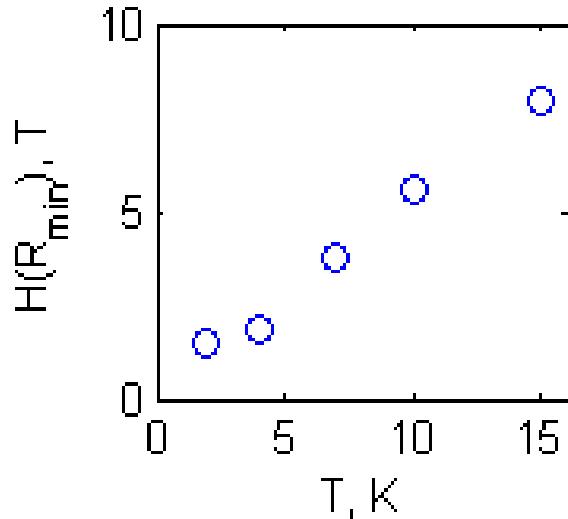
$$H = 4 \times 10^4 \text{ Oe}, I \parallel b$$

The temperature dependences of the magnetoresistance of TiS_3 , for the magnetic fields B directed along the three crystallographic axes.



The transverse magnetoresistance ($H \parallel c$) as a sum of linear negative and quadratic positive contributions

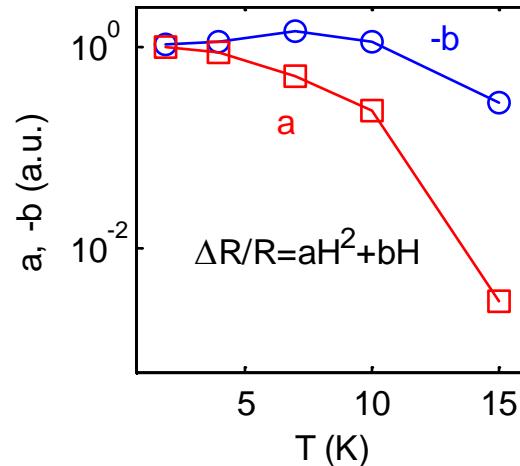
$$\Delta R/R = aH^2 + bH.$$



At H corresponding to the minimum of R :

$$\hbar\omega_c \approx kT$$

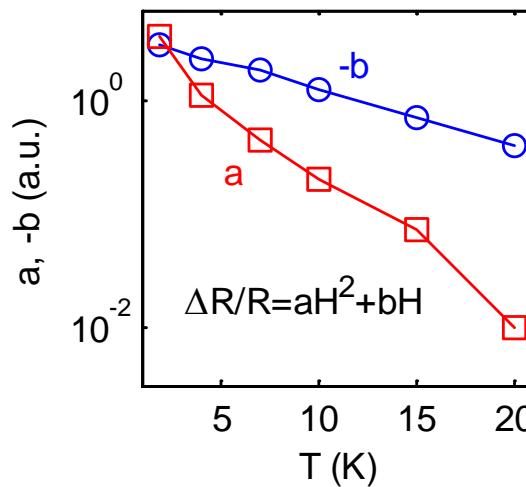
$$(\hbar\omega_c \equiv eH/m_e)$$



$$\Delta R/R = \mu^2 H^2$$

$$a = 10^0 \sim \mu = 400 \text{ cm}^2/\text{Vs}$$

$$a = 10^{-2} \sim \mu = 40 \text{ cm}^2/\text{Vs}$$



Possible mechanisms of magnetoresistance in TiS_3

Negative MR in transverse (out-of plane) fields, $B||c$

is observed in layered conductors with charge or antiferromagnetic ordering and is explained by localization induced by defects of different kind. E.g.:

$(\text{DMtTSF})_2\text{X}$, $\text{X} = \text{BF}_4^-$, ClO_4^- , ReO_4^- . AF ordering. 2D weak localization induced by disorder in the anion lattice.
J. P. Ulmet et al., Phys. Rev. B 38 7782 (1988).

$\alpha\text{-}(\text{BEDT-TTF})_2\text{I}_3$. Ferroelectric CO phase transition. 2D weak localization induced by disorder in I layers.
T. Ikek et al., PRB 96 (2017) 075141

$\alpha\text{-TaS}_3$ CDW. Delocalization of quantum interference of CDW loop formed in domain structure.
Katsuhiko Inagaki et al., Phys. Rev. B 93, 075423 (2016)

Positive MR in parallel (in-plane) fields, $B||l||b$, $B||a$

is observed in 2D interacting low-density carrier ($n \sim 10^{11} \text{ cm}^{-2}$) electron systems, 2D EG. **Si-MOS structures.**

Explanations:

Zeeman spin-splitting. *V. T. Dolgopolov and A. V. Gold, JETP Lett. 71, 27 (2000).*

Both the spin and Coulomb interaction effects *V. M. Pudalov et al., JETP Lett. 65, 932 (1997)*

The two parallel dissipation channels : scattering of the electrons by impurities in 2D Fermi liquid and Coulomb scattering of electrons by the collective localized states (spin droplets). *L. A. Morgan et al., Phys. Rev. B 93, 235145 (2016)*

Intermediate phase between the Fermi-liquid and the Wigner crystal phases. *B. Spivak, Phys. Rev. B 67, 125205 (2003)*

CONCLUSIONS

The magnetoresistance of whiskers of q-1D layered semiconductor TiS_3 was studied for current flowing along the metal chains ($I \parallel b$) and for the magnetic field B directed along the three crystallographic axes: ($B \parallel a$), ($B \parallel b$), ($B \parallel c$), $0 < B < 9$ T.

Angular dependences of magnetoresistance reveal quasi 2D nature of the electronic system for $T < 100$ K.

Anomalous behavior of $R(H)$ below $T_0 \approx 50$ K is observed. A negative transverse ($B \parallel c$) and positive longitudinal ($B \parallel b \parallel I$) magnetoresistance has been found.

The results indicate charge- or magnetic-ordering phase transition in 2D layers.